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28 June 2024

Sub: Registration for the Conference

Dear **Shamayeeta Dass**:

You would have already received the Letter of Acceptance for your Abstract

Abstract Number: **235**

Title of the paper**: Deep Learning Based Image Processing For Detection Of Manufacturing Defects**

from Prof. Amiya R. Mohanty, Chair, Technical Committee, WCEAM-2024.

May I request you to REGISTER for the Conference at the Conference website <https://wceam2024.com/register/> for in- person presentation.

You will be able to avail EARLY BIRD REGISTRATION till August 30, 2024.

Meanwhile, you may submit the camera-ready manuscript, at the conference website (<https://www.wceam2024.com/>) within the due date as per the guidelines.

In all correspondence, please quote the above Abstract Number.

With best regards



Nalinaksh S. Vyas

Conference Chair, WCEAM 2024